

Search Notes

Application/Control No.

10/661,204

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

LAIL ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
Search	Updated	2/07	hnh

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
385	100	2/07	hnh
385	102	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR